



### A 1MS/s to 1GS/s Ringamp-Based Pipelined ADC with Fully Dynamic Reference Regulation and Stochastic Scope-on-Chip Background Monitoring in 16nm

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#### **Architecture Overview**



- Ringamp "deep" pipeline based on: [Hershberg, ISSCC 2019, Paper 3.6] [Hershberg, ISSCC 2019, Paper 3.1]
  - Fully Dynamic Power Consumption
  - Asynchronous event-driven timing control
  - MDAC with passive-hold mode in STG1
  - Early quantization in STG2-9

- New in this work:
  - Reference Regulation
  - Stochastic Scope-on-Chip
  - Ringamp Topology

#### Outline

- Ringamp Topology
- Fully Dynamic Reference Regulation
- Scope-on-Chip Amplifier Settling Monitor
- Performance Summary & Conclusion

- What is a ringamp?
  - Multi-stage amplifier
  - Dominant output pole
  - Dynamic stabilization
- High efficiency
- High linearity
- High speed
- Wide output swing
- Sully dynamic (switchable)
- Scales with Digital



#### [Hershberg, JSSC 2012]

- Fully-Differential
- Multi-Path CMFB
- Trapped-Charge Biasing
- CMOS-Resistor
- Bias-Enhanced
- Self-Resetting
- Slew-Done Detector



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[Lim, JSSC Dec. 2015]

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• Slew-Done Detector

[Lim, JSSC Dec. 2015] [Hershberg, ISSCC 2019] (Paper 3.1)



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[Lagos, JSSC Feb. 2019]



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[Chen, TCASII 2018] [Lagos, JSSC Mar. 2019]



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Not Mandatory Using a fixed timedelay to generate *slew done* also ok.

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### Fully Dynamic Reference Regulation

- Goal: fully dynamic power for complete system (core + reference)
  - Constant FoM for any clock rate
  - Enables reconfigurable, multi-standard ADCs
- ADC core fully dynamic by design  $\checkmark$ 
  - Enabler: Asynchronous timing control
  - Enabler: Ring amplifier with fast on/off switching
- Reference Regulation
  - How can we make this fully dynamic too?

[Hershberg, ISSCC 2019, Paper 3.6]

### Fully Dynamic Reference Regulation

- Discrete Time Regulator Loop
  - Comparator monitors replica level
  - Feeds back "charge packet" ( $C_P$ ) update into charge reservoir ( $C_R$ )



[Kull, JSSC 2013]

### Fully Dynamic Reference Regulation

- Discrete Time Regulator Loop
  - Comparator monitors replica level
  - Feeds back "charge packet" ( $C_P$ ) update into charge reservoir ( $C_R$ )
- Limitations
  - Must source all charge for an ADC conversion in a single charge packet
  - Reference ripple error a problem
  - Acceptable for ADCs < 8 bit</p>
  - $-C_R$  too large for ADCs > 8 bit (> 1nF)



[Kull, JSSC 2013]

- Key observation: V<sub>RFF</sub> accuracy & current requirements are decoupled w.r.t. time
  - Initial: large current, low accuracy
  - Final: small current, high accuracy



Example Settling Waveform

OUTp OUTm

slew done

Хp Xm

900

- **Key observation:** V<sub>REF</sub> accuracy & current requirements are decoupled w.r.t. time
  - Initial: large current (98%), low accuracy
  - Final: small current (2%), high accuracy



Example Settling Waveform

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slew done

Xp Xm

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- **Key observation:** V<sub>REF</sub> accuracy & current requirements are decoupled w.r.t. time
  - Initial: large current (98%), low accuracy
  - Final: small current (2%), high accuracy

#### True for many applications

- Residue Amplifiers (Slew->Settle)
- SAR DACs (MSB->LSB)



- Solution: Use 2 copies of  $V_{REF}$ 
  - V<sub>REF</sub> dirty: low-impedance, low-accuracy
  - $V_{REF}$  clean: high-impedance, high-accuracy
- Relaxes requirements of both copies



Example Settling Waveform



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#### Switching from Dirty to Clean Reference



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#### Switching from Dirty to Clean Reference

- Need break-before-make
  - Must isolate clean from dirty
- Want fast & clean crossover
  - Amplifier feedback is "paused", time lost
  - Any injected errors must be re-settled



Example Settling Waveform

OUTp OUTm

slew done

Хp Xm

900

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0.6

0.4

### Sub-DAC Design Details

- Optimized control logic
  - Non-overlap
  - Fast crossover (< 30ps)
  - No corruption of *REF\_clean*
- Dummy switches to cancel clock feedthrough & charge injection
- Minimal impact on settling performance

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#### **Reference Generation**



- Single set of regulated references shared by all stages
  - Regulators only update once per cycle

- Standard Pipeline
  - VREFP
  - VCM
  - VREFM
- Here: 5 discrete-time loops
  - VREFP dirty
  - VREFP clean
  - VCM
  - VREFM dirty
  - VREFM clean











#### • $C_P$ / $C_M$ sizing

- Determined by max current pulled by load
- C<sub>R</sub> sizing
  - Determined by reference ripple amplitude requirements (accuracy / noise)



- $C_P / C_M$  sizing
  - Determined by max current pulled by load

#### • C<sub>R</sub> sizing

 Determined by reference ripple amplitude requirements (accuracy / noise)



- Dirty REF accuracy limited by reference ripple
  - Function of  $C_P/C_M$  vs.  $C_R$
- Clean REF accuracy limited by comparator noise
  - Over-designed for low-noise
  - Can decimate to save power (only operate once every N cycles)



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### **Regulator Design Values**

- All capacitors made tunable for testing purposes
- Regulator area can be significantly reduced
  - Many non-essential test features

Nominal Capacitor Values

	CP	CM	CR
VCM	130 fF	130 fF	45 pF
VREFP_dirty	4pF	-	45 pF
VREFM_dirty	-	2 pF	45 pF
VREFP_clean	320 fF	24 fF	120 pF
/REFM_clean	20 fF	320 fF	120 pF

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#### 2 Approaches to Ringamp Robustness

- Robust by design
  - No calibration, but needs design margin
  - Several SoTA designs using this:

[Hung, ISSCC 2020] 100MS/s, 71.7dB SNDR, 2.2fJ/c-step FoM<sub>W</sub> [Lim, JSSC Dec. 2015] 50MS/s, 70.9dB SNDR, 6.9fJ/c-step FoM<sub>W</sub> [Lim, VLSI 2017] 100MS/s, 73.2dB SNDR, 6.1fJ/c-step FoM<sub>W</sub>

- Robust by background tuning / calibration / digital assistance
  - Max performance, but possibly more complex
  - Less has been tried here interesting research questions!
    [Hershberg, ISSCC 2019, Paper 3.1]

### **Ringamp Waveform Capture**

#### • Main goals:

- 1. Background capture of amplifier settling waveform
- 2. Use this information to optimize ringamp biasing / performance





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Challenge 3: Low complexity



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Challenge 3: Low complexity

V<sub>IN</sub> + 1,1,0,1,0,0,1,... avg D(V<sub>IN</sub>)

# **Solution:** 1-bit stochastic ADC



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- Monitor circuit added to output of each stage
- Single-ended scheme here
  - Dummy sampler also on OUTp
  - Fully differential also possible





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#### **Measured Amplifier Settling Waveforms**

- Provides direct insight into amplifier settling behavior!
  - Verification
  - Debug
  - Calibration?...



### **Ringamp Waveform Capture**

#### • Main goals:

- 1. Background capture of amplifier settling waveform  $\checkmark$
- 2. Use this information to optimize ringamp biasing / performance



### **Defining an Objective Function for Bias Control**

- Observation: only the Critically Damped case has:
  - Initial large amplitude
  - Final small amplitude
- Estimator = P<sub>2</sub> / P<sub>1</sub>
- Other variations of this concept also work



### **Defining an Objective Function for Bias Control**

- Estimator =  $P_2 / P_1$
- Accurately predicts the bias optimum (within certain margin)
- PVT tracking loop possible
  - But not implemented



#### Background operation of Ringamp Monitor

- Monitor circuit samples during normal operation
  - Disturbs residue slightly

- Minimal performance impact  $\checkmark$ 
  - SNDR: no loss
  - THD: no loss
  - SFDR: -3dB worst-case



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#### **Measurement Results**

- 16nm CMOS FinFET
- 0.095 mm<sup>2</sup>



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#### **ADC Output Spectrum with Regulation**



#### **Frequency Sweeps**



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### **Regulator Performance**

- Regulator only 8% of total ADC power
  - Majority of power delivered to load
  - High efficiency
- Decimation of clean regulators improves efficiency
- Minimal impact on noise & SNDR



#### **Performance Summary**

- 1GS/s single channel 9.6 ENOB
- Full dynamic reference regulation
- FoM<sub>w</sub> 14fJ/c-step from 1MS/s 1GS/s

Technology	16nm CMOS	
Supply	0.9 V	
Sampling Rate	1MS/s - 1 GS/s	
Resolution	11b	
Input Range	1.6 V pk-pk diff.	
Performance at 1GS/s:	100 MHz input:	500 MHz input:
ENOB	9.7 b	9.6 b
SNDR	59.8 dB	59.5 dB
SFDR	78.6 dB	75.9 dB
THD	71.8 dB	69.9 dB
Total Power	10.9 mW	
ADC	10.0 mW (92%)	
Regulator	0.9 mW (8%)	
Walden FoM	14.1 fJ/c-step	
Schreier FoM	166.1 dB	
Active Area	0.095 mm <sup>2</sup>	

#### **Contributions & Conclusions**

- High-Speed Ringamp Topology
  - Elegant operation
- Fully-Dynamic Discrete-Time Reference Regulation
  - Many applications (pipeline, SAR, ...)
  - Any accuracy / noise requirement
- Stochastic ADC "Scope-on-Chip"
  - Small, simple, high resolution, background operation
  - Other interesting applications: e.g. supply and reference diagnostics

#### Thank you for your attention!



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